

Publications

1. Shuo-Cheng Wang, Ching-Fa Yeh, Chun-Yen Liu, **Chen-Wei Chiang** and Jen-Chung Lou, "NH₃ plasma treatment and defect passivation on the electrical characteristics of poly-Si TFT," *IEDMS*, p. 489, 2004.



Vita

Chen-Wei Chiang was born on July 26, 1981 in Taipei County, Taiwan, R. O. C.. He received the B.S. degree in electronic engineering at National Kaohsiung University of Applied Sciences (KUAS), Kaohsiung, Taiwan, R. O. C., in 2003. He is currently working toward the M.S. degree in Electronic Engineering at Institute of Electronics, National Chiao-Tung University, Hsin-Chu, Taiwan, R. O. C.. The topic of this thesis is “Improving reliability characteristics of TFTs by T-gate structure and NH_3 passivation”.

